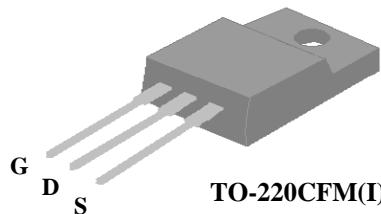




- ▼ Lower On-resistance
- ▼ Simple Drive Requirement
- ▼ Fast Switching Characteristic

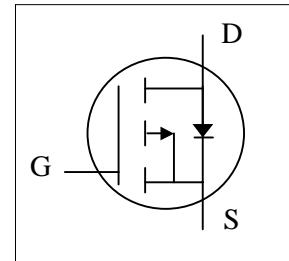


| | |
|--------------|-------|
| BV_{DSS} | -100V |
| $R_{DS(ON)}$ | 160mΩ |
| I_D | -12A |

Description

Advanced Power MOSFETs from APEC provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220CFM isolation package is widely preferred for commercial-industrial through hole applications.



Absolute Maximum Ratings

| Symbol | Parameter | Rating | Units |
|---------------------------|--|------------|-------|
| V_{DS} | Drain-Source Voltage | -100 | V |
| V_{GS} | Gate-Source Voltage | ± 32 | V |
| $I_D @ T_C = 25^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V$ | -12 | A |
| $I_D @ T_C = 100^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V$ | -10 | A |
| I_{DM} | Pulsed Drain Current ¹ | -48 | A |
| $P_D @ T_C = 25^\circ C$ | Total Power Dissipation | 31.25 | W |
| | Linear Derating Factor | 0.25 | W/°C |
| E_{AS} | Single Pulse Avalanche Energy ² | 40 | mJ |
| I_{AR} | Avalanche Current | -9 | A |
| T_{STG} | Storage Temperature Range | -55 to 150 | °C |
| T_J | Operating Junction Temperature Range | -55 to 150 | °C |

Thermal Data

| Symbol | Parameter | Value | Units |
|-------------|--|-------|-------|
| R_{thj-c} | Maximum Thermal Resistance, Junction-case | 4.0 | °C/W |
| R_{thj-a} | Maximum Thermal Resistance, Junction-ambient | 65 | °C/W |



Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Units |
|--|--|--|------|------|-----------|---------------------------|
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{\text{GS}}=0\text{V}$, $I_{\text{D}}=-250\mu\text{A}$ | -100 | - | - | V |
| $\Delta \text{BV}_{\text{DSS}}/\Delta T_j$ | Breakdown Voltage Temperature Coefficient | Reference to 25°C , $I_{\text{D}}=-1\text{mA}$ | - | -0.1 | - | $\text{V}/^\circ\text{C}$ |
| $R_{\text{DS(ON)}}$ | Static Drain-Source On-Resistance ³ | $V_{\text{GS}}=-10\text{V}$, $I_{\text{D}}=-8\text{A}$ | - | - | 160 | $\text{m}\Omega$ |
| | | $V_{\text{GS}}=-4.5\text{V}$, $I_{\text{D}}=-6\text{A}$ | - | - | 200 | $\text{m}\Omega$ |
| $V_{\text{GS(th)}}$ | Gate Threshold Voltage | $V_{\text{DS}}=V_{\text{GS}}$, $I_{\text{D}}=-250\mu\text{A}$ | -1 | - | -3 | V |
| g_{fs} | Forward Transconductance | $V_{\text{DS}}=-10\text{V}$, $I_{\text{D}}=-8\text{A}$ | - | 14 | - | S |
| I_{DSS} | Drain-Source Leakage Current | $V_{\text{DS}}=-100\text{V}$, $V_{\text{GS}}=0\text{V}$ | - | - | -1 | uA |
| | Drain-Source Leakage Current ($T_j=125^\circ\text{C}$) | $V_{\text{DS}}=-80\text{V}$, $V_{\text{GS}}=0\text{V}$ | - | - | -250 | uA |
| I_{GSS} | Gate-Source Leakage | $V_{\text{GS}}=\pm 32\text{V}$, $V_{\text{DS}}=0\text{V}$ | - | - | ± 100 | nA |
| Q_g | Total Gate Charge ³ | $I_{\text{D}}=-8\text{A}$ | - | 16 | 25.6 | nC |
| Q_{gs} | Gate-Source Charge | | - | 4.4 | - | nC |
| Q_{gd} | Gate-Drain ("Miller") Charge | | - | 8.7 | - | nC |
| $t_{\text{d(on)}}$ | Turn-on Delay Time ³ | $V_{\text{DS}}=-50\text{V}$ | - | 9 | - | ns |
| t_r | Rise Time | | - | 14 | - | ns |
| $t_{\text{d(off)}}$ | Turn-off Delay Time | $R_G=3.3\Omega$, $V_{\text{GS}}=-10\text{V}$ | - | 45 | - | ns |
| t_f | Fall Time | | - | 40 | - | ns |
| C_{iss} | Input Capacitance | $V_{\text{GS}}=0\text{V}$ | - | 1590 | 2550 | pF |
| C_{oss} | Output Capacitance | | - | 110 | - | pF |
| C_{rss} | Reverse Transfer Capacitance | | - | 70 | - | pF |
| R_g | Gate Resistance | f=1.0MHz | - | 8 | 12 | Ω |

Source-Drain Diode

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Units |
|-----------------|------------------------------------|---|------|------|------|-------|
| V_{SD} | Forward On Voltage ³ | $I_{\text{S}}=-12\text{A}$, $V_{\text{GS}}=0\text{V}$ | - | - | -1.3 | V |
| t_{rr} | Reverse Recovery Time ³ | $I_{\text{S}}=-8\text{A}$, $V_{\text{GS}}=0\text{V}$, $dI/dt=-100\text{A}/\mu\text{s}$ | - | 49 | - | ns |
| Q_{rr} | Reverse Recovery Charge | | - | 110 | - | nC |

Notes:

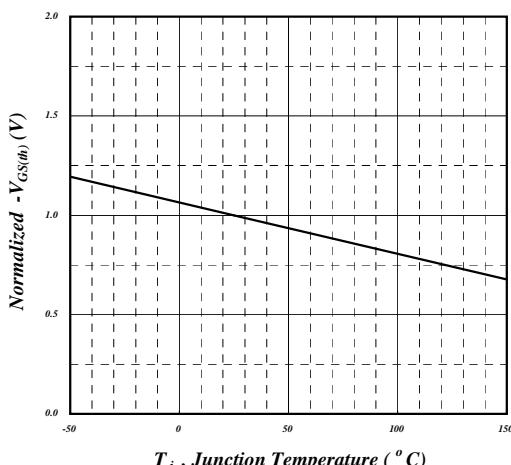
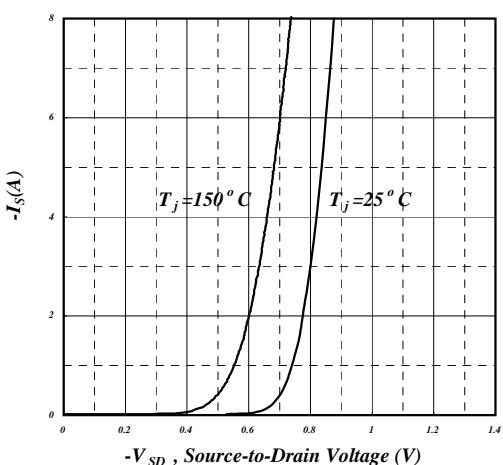
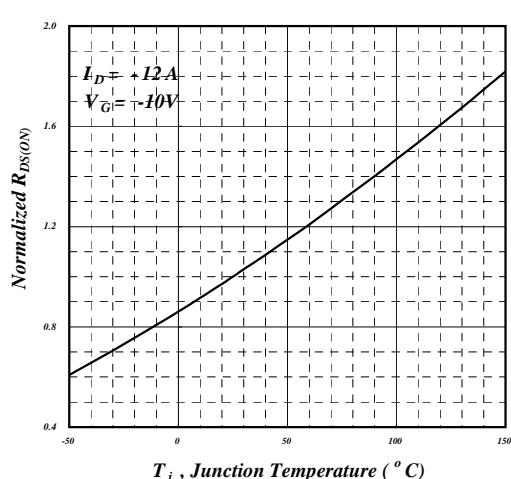
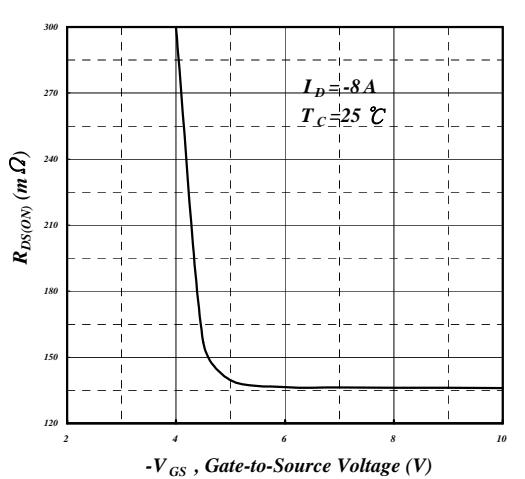
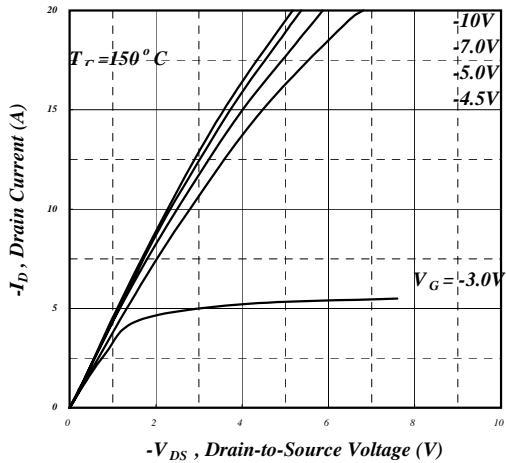
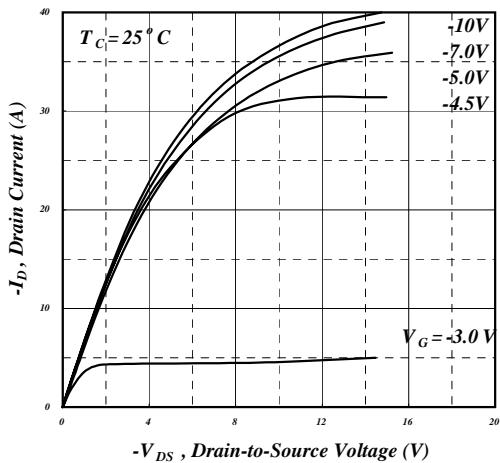
- 1.Pulse width limited by Max. junction temperature.
- 2.Starting $T_j=25^\circ\text{C}$, $V_{\text{DD}}=-50\text{V}$, $L=1.0\text{mH}$, $R_G=25\Omega$.
- 3.Pulse test

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

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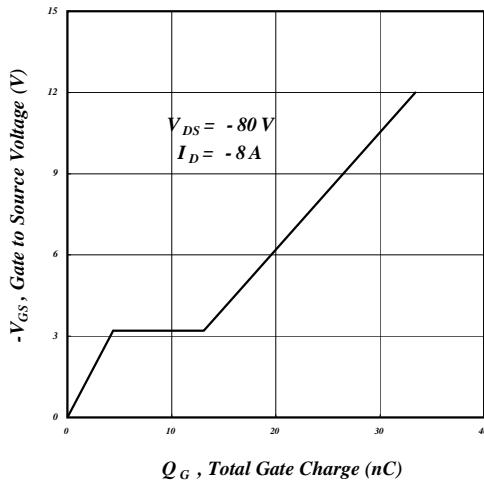


Fig 7. Gate Charge Characteristics

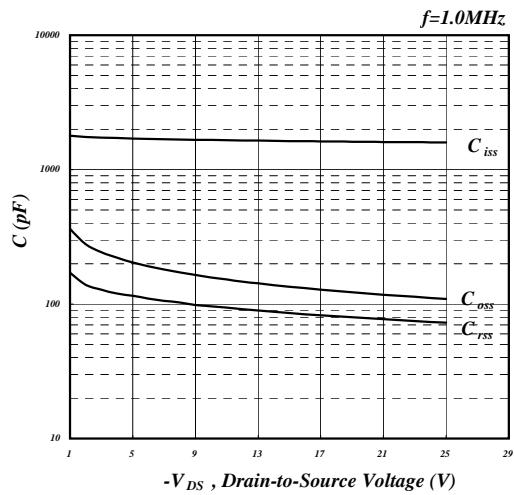


Fig 8. Typical Capacitance Characteristics

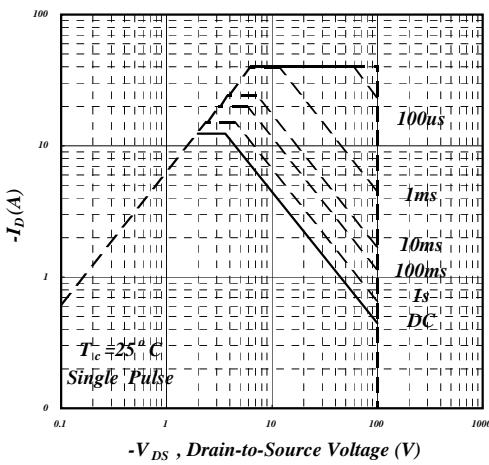


Fig 9. Maximum Safe Operating Area

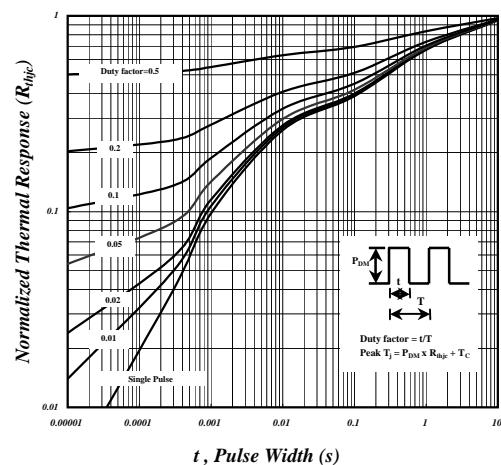


Fig 10. Effective Transient Thermal Impedance

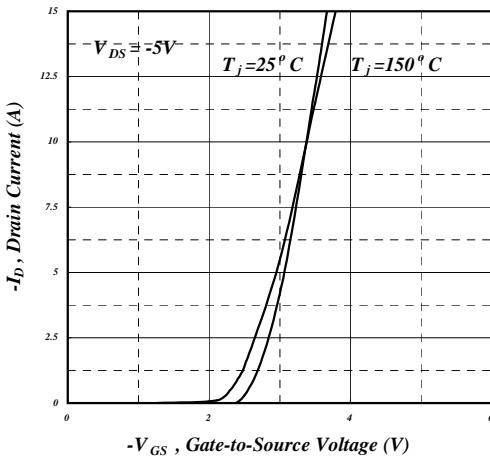


Fig 11. Transfer Characteristics

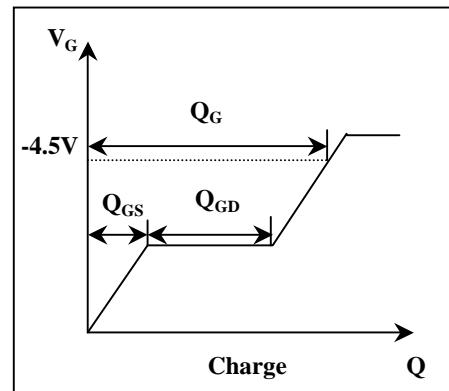


Fig 12. Gate Charge Waveform